Analytical Reference Materials International



Certificate of Analysis Certified Reference Material

Grade: **AISI 321 / UNS S32100**Part Number (Q.A. NO.): **IARM 6I**

Certificate Date: **07/20/2017** Certificate No.: **6I-07202017-IARM-F** Revision Date: **10/11/2017**

Interpretation of Data

- 1. Certified values listed below reflect analysis results submitted by qualified analytical laboratories using a combination of methods and instrumentation that emulate actual methods and instrumental techniques currently utilized in the analytical community and are reported as % wt. unless otherwise noted.
- 2. Any data reported and enclosed by a **parentheses** () is a "best estimate" and is **NOT CERTIFIED**. This data could not be quantified sufficiently for certification. It was however, reported by enough laboratories to be considered as potentially present in the matrix of the material being examined.
- 3. The "Inter laboratory Analysis Program" (ILAP) utilized in the establishment of the data are an ongoing program with permanent membership. Certain elements may be selected by a consensus of the members for more extensive testing. Therefore the data in brackets [] indicates further testing is in process. Chips are not certified for Oxygen analysis.
- 4. The "±Estimated Uncertainty" is enclosed by a parentheses () below the individual element's concentration and is based on a Confidence Interval at 95%. Included in this estimated uncertainty, are the combined effects of method imprecision, material inhomogeneity, and any bias between methods.

Important: A "User Registration Card" accompanies all shipments. This card should be completed immediately upon receipt of materials with the appropriate user information. This is the only way in which ARMI can guarantee customer updates or possible data modifications!

Aluminum	Antimony	Arsenic	Boron	Calcium	Carbon	<u>Cerium</u>	Chromium	Cobalt
0.084	(0.0008)	(0.005)	0.0034	(0.0004)	0.049	(<0.005)	17.76	0.052
(0.005)			(0.0009)		(0.001)		(0.06)	(0.003)
Copper	Hydrogen	Lead	Magnesium	Manganese	Molybdenum	Nickel	<u>Niobium</u>	Nitrogen
0.202	(<0.001)	(<0.02)	(<0.03)	1.76	0.133	9.20	0.018	0.013
(0.005)				(0.02)	(0.006)	(0.06)	(0.004)	(0.002)
<u>Oxygen</u>	Phosphorus	Selenium	Silicon	<u>Sulfur</u>	Tantalum	<u>Tin</u>	<u>Titanium</u>	Tungsten
0.0012	0.0208	(<0.03)	0.31	0.023	(<0.01)	0.0060	0.60	0.023
(0.0002)	(0.0008)		(0.01)	(0.005)		(0.0007)	(0.02)	(0.008)
Vanadium	Zinc	Zirconium						
0.048	(0.003)	(0.003)						
(0.004)								

The laboratories participating in the "Inter-Laboratory Analysis Program" (ILAP) and certification of this material are as follows:

AADFW, Inc. - Euless, TX Laboratorio Prove Materiali S. Marco srl - Schio, Italy

Certified Alloy Products - Long Beach, CA

Laboratory Testing, Inc. - Hatfield, PA

Crucible Industries - Syracuse, NY

MetalTek International, Inc. - Waukesha, WI

Davis Alloys Manufacturing, LLC - Sharpsville, PA Microlab - TamilNadu, India Dirats Laboratories - Westfield, MA PM Kalco, Inc - Wheatland, PA

Ellwood National Steel - Irvine, PA

Traceability: All members of the "Inter-Laboratory Analysis Program" (ILAP) listed above validate test methods and instrument performance utilizing SRMs produced by the National Institute of Standards and Technology, (NIST) as well as other CRMs and RMs produced by recognized Certifying

Bodies from around the world. The specific SRMs, CRMs, and RMs applicable to the material covered by this certificate are:

ALPHA AR882 BCS 346 **IARM 346** ALPHA AR1650 BS 85D IARM 6G NIST 1185 **NIST 363** ALPHA AR654 ALPHA AR882 BS 321C IARM 162C IARM 35J ALPHA AR656 ALPHA AR890 BS 321D IARM 163D IARM 6B MBH 13X32100A NIST 3155 NIST 898 ALPHA AR661 ASTM 9911 BS 602C IARM 289A IARM 6E MBH 321 NIST 3169 **NIST 899** ALPHA AR881 ASTM 9912 IARM 2C IARM 6F

A specific line of traceability is established to NIST and other Certifying Bodies for those elements that are noted as "Certified Values" on the Certificates of Analyses referenced above.

The following data and accompanying statements represent all pertinent information reported in the ILAP as it applies to the chemical characterization of this material as of 10/11/2017.

61	Al	Sb	As	В	Ca	С	Ce	Cr	Co	Cu	Н	Pb	Mg	Mn	Мо	Ni
1	0.070	0.0007	0.0036	0.0022	0.0003	0.0459	<0.0001	17.628	0.043	0.185	0.0003	0.00002	0.0014	1.717	0.12	9.060
2	0.0769	0.0008	0.0036	0.0024	0.0003	0.047	< 0.0001	17.64	0.0469	0.1966		0.0023	0.023	1.725	0.1250	9.118
3	0.079	0.0009	0.0037	0.0027	0.0005	0.0473	< 0.005	17.700	0.0478	0.198		0.018	< 0.0001	1.733	0.1251	9.13
4	0.0817	< 0.004	0.004	0.0030	0.0005	0.0479		17.702	0.0498	0.198		< 0.0001		1.740	0.126	9.155
5	0.082		0.0074	0.0034		0.048		17.733	0.0516	0.2000		< 0.0001		1.742	0.1288	9.164
6	0.083			0.0038		0.0491		17.75	0.052	0.20				1.743	0.130	9.2018
7	0.0845			0.0046		0.0496		17.7689	0.053	0.201				1.753	0.1313	9.204
8	0.0848			0.0051		0.050		17.79	0.053	0.205				1.76	0.1336	9.2267
9	0.0876					0.0506		17.808	0.0538	0.208				1.7629	0.135	9.23
10	0.088					0.0507		17.8135	0.055	0.2081				1.7739	0.1394	9.327
11	0.0939					0.051		17.863	0.063	0.2101				1.775	0.147	9.3394
12	0.1005					0.0524		17.949		0.2102				1.7756	0.149	
13														1.8191		
14																
15																
Mean	0.084	0.0008	0.004	0.0034	0.0004	0.049		17.76	0.052	0.202	0.0003	0.007	0.012	1.76	0.133	9.20
STDV.	0.008	0.0001	0.002	0.0010	0.0001	0.002		0.09	0.005	0.007		0.010	0.015	0.03	0.009	0.08
Certified	0.084	(0.0008)	(0.005)	0.0034	(0.0004)	0.049	(<0.005)	17.76	0.052	0.202	(<0.001)	(<0.02)	(<0.03)	1.76	0.133	9.20
95% C.I.	0.005		,	0.0009		0.001	,	0.06	0.003	0.005		•	,	0.02	0.006	0.06
Methods	X,O,I	O,IM,A	O,IM,A	O,I	O,I	O,C	O,IM	X,O	X,O,I	X,O,I		O,IM,A	O,IM	X,O,I	X,O,I	X,O

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, 1 = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES

6l	Nb	N	0	P	Se	Si	S	Ta	Sn	Ti	W	V	Zn	Zr	
1	0.011	0.0093	0.0009	0.019	0.00001	0.258	0.005	0.0001	0.0042	0.5594	0.0052	0.0350	0.00001	0.00002	
2	0.0131	0.0109	0.0011	0.019	0.0014	0.2698	0.0052	0.0069	0.0048	0.580	0.0127	0.0423	0.0004	0.0003	
3	0.014	0.0114	0.0012	0.0192	0.029	0.293	0.0227	< 0.0001	0.0052	0.58	0.0136	0.0466	0.0039	0.001	
4	0.014	0.0121	0.0013	0.0200	< 0.0001	0.30	0.0229	< 0.0020	0.0056	0.59	0.0170	0.047	0.006	0.0029	
5	0.0158	0.0123	0.0013	0.020		0.3100	0.024	< 0.01	0.0059	0.5902	0.0207	0.0476	< 0.0001	0.006	
6	0.0164	0.013	0.0014	0.0209		0.3185	0.0260		0.0060	0.594	0.022	0.049		0.0084	
7	0.0168	0.013	0.0014	0.021		0.3201	0.026		0.0060	0.595	0.0300	0.0496		< 0.0001	
8	0.0174	0.0146		0.021		0.322	0.0262		0.006	0.5954	0.0314	0.050			
9	0.020	0.0158		0.021		0.322	0.0264		0.0067	0.5997	0.036	0.050			
10	0.027	0.0159		0.0211		0.323	0.0265		0.0075	0.6076	0.037	0.051			
11	0.028	0.02		0.0225		0.3277	0.0272		0.008	0.6206		0.051			
12				0.0225		0.333	0.0276			0.641		0.0622			
13				0.0235		0.3341	0.028			0.669					
14															
15															
Mean	0.018	0.013	0.0012	0.0208	0.010	0.31	0.023	0.004	0.0060	0.60	0.023	0.048	0.003	0.003	
STDV.	0.005	0.003	0.0002	0.0014	0.016	0.02	0.008	0.005	0.0011	0.03	0.011	0.006	0.003	0.003	
Certified	0.018	0.013	0.0012	0.0208	(<0.03)	0.31	0.023	(<0.01)	0.0060	0.60	0.023	0.048	(0.003)	(0.003)	
95% C.I.	0.004	0.002	0.0002	0.0008		0.01	0.005		0.0007	0.02	0.008	0.004			
Methods	X,O,IM,I	O,F	F	X,O,I	O,IM,I,A	X,O,I	O,C	X,O,IM,I	X,O,IM,A	X,O,I	X,O,I	X,O,I	O,IM,A	X,O,IM	

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES

The International Standards Organization (ISO) definitions, expressed in ISO Guide 30–1992 list the following:

Certifying Body: Any technically competent body (organization or firm, public or private) that issues a reference material certificate, which provides the information, detailed in ISO Guide 31. The only generally accepted certifying body in the United States for primary standards - Standard Reference Materials (SRM) is the U. S. Department of Commerce, National Institute of Standards & Technology, (NIST), Gaithersburg, MD. All other certifying bodies in the United States produce Reference Materials (RM) or Certified Reference Materials (CRM).

Reference Material (RM): Material or substance one or more of whose property values are sufficiently homogeneous and well established to be used for the calibration of an apparatus, the assessment of a measurement method, or for assigning values to materials.

Certified Reference Material (CRM): Reference material, accompanied by a certificate, one or more of whose property values are certified by a procedure, which establishes its traceability to an accurate realization of the unit in which the property values are expressed, and for which each certified value is accompanied by an uncertainty at a stated level of confidence.

Inter-Laboratory Analysis Program (ILAP): Although ASTM Standard E691-87 applies to inter-laboratory studies to "Determine the Precision of a Single Test Method", it is also a well thought out and logical plan for conducting an inter laboratory program involving multiple techniques. Therefore, the planning, conducting, analyzing, protocol, and treatment of data resulting from this inter laboratory program were performed utilizing the guidelines established in ASTM E691-87.

Methods of Analysis: In view of the fact, that the "Inter Laboratory Analysis Program" entails a wide variety of materials, no single analytical method would provide optimum data results. Therefore, the methods utilized were a combination of ASTM Standard Methods for classical wet chemistry, ICP, AA, Optical Emission, and X-Ray spectrometric methods. The determinations for Carbon, Sulfur, Nitrogen, and Oxygen are the result of combustion and OE instrument procedures.

Expiration of Certification: The certification of this IARM is valid indefinitely, within the uncertainty specified, provided the IARM is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the IARM is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.

Instructions for Use: The test surface is the side opposite to the labeled surface, which includes the IARM number. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing as these processes may contaminate the surface. When not in use, the material should be stored in a cool, dry location. This material was tested using both the solid disks and chips prepared from the disks. The certified values are considered representative of the overall average composition of the material. Chips are not to be used for Oxygen analysis.

Selection of Materials: A "batch" or "series" is defined as a single bar of one continuous length and heat. The majority of materials are in wrought condition; other methods of manufacture are utilized as a less desirable resort. ILAP samples are taken by removing a section, a minimum of, every one-twelfth of total length from the entire bar. A portion of the section is converted to chips and thin (pin) disk for analysis by classical wet chemistry, ICP, AA, and combustion procedures, and the balance remains as a thick disk for OES and X-Ray analysis. This systematic sampling procedure results in the homogeneity being reflected as a product of the overall statistics and certified data. This method of homogeneity testing is in accordance with ISO Guide 34, regarding the systematic selection and testing of a representative number of units for the assessment of homogeneity.

David Coler, General Manager

Analytical Reference Materials International

ISO 9001:2008

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